

# Resource Summary Report

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## Delaware University Surface Analysis Core Facility

RRID:SCR\_017796

Type: Tool

### Proper Citation

Delaware University Surface Analysis Core Facility (RRID:SCR\_017796)

### Resource Information

**URL:** <http://www.udel.edu/chem/beebe/surface.htm>

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**Description:** Core provides consulting and services in X-ray Photoelectron Spectroscopy (XPS or ESCA), Time-of-Flight Secondary-Ion Mass Spectrometry (TOF-SIMS), X-ray Photoelectron Imaging, Auger Electron Spectroscopy (AES), Scanning Auger Microscopy or Imaging (SAM), Secondary-Electron Microscopy (SEM), Ion-Scattering Spectroscopy (ISS or LEIS), Scanning Probe Microscopy (STM and AFM).

**Synonyms:** Surface Analysis Facility

**Resource Type:** access service resource, core facility, service resource

**Keywords:** Surface, analysis, X-ray, photoelectron, spectroscopy, ion, mass, spectrometry, imaging, Auger, microscopy, scattering, scanning, probe, service, core

**Funding:** NSF

**Availability:** Open

**Resource Name:** Delaware University Surface Analysis Core Facility

**Resource ID:** SCR\_017796

**Alternate IDs:** ABRF\_439

**Record Creation Time:** 20220129T080337+0000

**Record Last Update:** 20260805T044417+0000

### Ratings and Alerts

No rating or validation information has been found for Delaware University Surface Analysis Core Facility.

No alerts have been found for Delaware University Surface Analysis Core Facility.

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## Data and Source Information

**Source:** [SciCrunch Registry](#)

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## Usage and Citation Metrics

We have not found any literature mentions for this resource.